



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L ULTW 16.0003-07	Issue No.:	7	Status:	Current
Additional Site to Certification: IECQ-L ULTW 16.0003 Originally Issued: 2016/07/28					
Supersedes:	IECQ-L ULTW 16.0003-07 Issue 6		Issue Date:	2024/08/29	Site Added: 2016/07/28
CB Reference No.:	50600097 ITL		Expiration:	2025/07/27	

Materials Analysis Technology Inc.

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

The materials analysis, chemical analysis and failure analysis of semiconductors.
See attached Schedule.

-- Attached Schedule: IECQ-L_ULTW_50600097 ITL_08-29-24.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road,
Feng Yuan Dist., Taichung City
Taiwan

Authorized person:
Bob CHEN



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-07

CB Certificate No.: 50600097 ITL

Schedule Number: IECQ-L ULTW 16.0003-07-S Rev No.: 7 Revision Date: 2024/08/29 Page 1 of 1

Appendix-1 (50600097 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Transmission Electron Microscope (TEM)	T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Emission Microscopy (EMMI)-InGaAs	T-EFA-3
Optical Microscope (OM)	T-OMI-3
IC Layout Imaging	T-OMI-3
Decapsulation- Chemical	T-LAB-3
Delayer	T-LAB-3
Thermal Emission Microscope (THEMOS)	T-EFA-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
3D Optical Microscope (3D OM)	T-LAB-3

Technical Reviewer of DQS: Paul Yang Date: 8/29/2024

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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

